



<b>Title of Change:</b>	Wafer top metal change and Au to Cu wire conversion for SOT23 Low VCEsat transistors	
<b>Proposed First Ship date:</b>	28 Sep 2021 or earlier if approved by customer	
<b>Contact Information:</b>	Contact your local ON Semiconductor Sales Office or <a href="mailto:Andy.Tao@onsemi.com">Andy.Tao@onsemi.com</a>	
<b>PCN Samples Contact:</b>	Contact your local ON Semiconductor Sales Office or < <a href="mailto:PCN.samples@onsemi.com">PCN.samples@onsemi.com</a> >. Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.	
<b>Additional Reliability Data:</b>	Contact your local ON Semiconductor Sales Office or <a href="mailto:Dustin.Tenney@onsemi.com">Dustin.Tenney@onsemi.com</a>	
<b>Type of Notification:</b>	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <a href="mailto:PCN.Support@onsemi.com">PCN.Support@onsemi.com</a>	
<b>Marking of Parts/ Traceability of Change:</b>	At the expiration of this PCN devices will be assembled with 2 mil bare Cu wire at ON Semiconductor's existing Leshan facility. Products assembled with 2 mil bare Cu wire from the ON Semiconductor facility will have a Finish Goods Date Code of WW36' 2021 or greater.	
<b>Change Category:</b>	Wafer Fab Change, Assembly Change	
<b>Change Sub-Category(s):</b>	Material Change	
<b>Sites Affected:</b>		
<b>ON Semiconductor Sites</b>	<b>External Foundry/Subcon Sites</b>	
Leshan Phoenix Semiconductor, China	None	
ON Semiconductor Seremban, Malaysia		
<b>Description and Purpose:</b>		
<p>ON Semiconductor is notifying customers of its use of 2 mil bare Cu wire for SOT23 Low VCEsat transistor devices at ON Semiconductor's Leshan, China facility ,while changing the wafer top metal from 20KA AISi to 1.5KA TiW+ 20KA AISi</p> <p>Upon the expiration of this PCN, these devices will be built with 2 mil bare Cu wire at the same site. Datasheet specifications and product electrical performance remain unchanged. Reliability Qualification and full electrical characterization over temperature has been performed</p>		
	<b>Before Change Description</b>	<b>After Change Description</b>
Bond Wire	2 mil Au wire	2mi bare Cu wire
Wafer top metal	20KA AISi	1.5KA TiW+ 20KA AISi

**Reliability Data Summary:**QV DEVICE NAME: NSV1C200LT1G – PNPRMS: 75941PACKAGE: SOT-23

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs	0/240
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/240
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15,000 cyc	0/240
TC	JESD22-A104	Ta= -65°C to + 150°C	1000 cyc	0/240
HAST	JESD22-A110	110°C, 85% RH, 18.8psig, bias	528 hrs	0/231
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	92 hrs	0/240
PC	J-STD-020 JESD-A113	MSL 1 @ 260 °C		

**Electrical Characteristics Summary:**

Three temperature characterization and ESD performance has been performed, Electrical characterization result is available upon request.

**List of Affected Parts:**

**Note:** Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the [PCN Customized Portal](#).

Part Number	Qualification Vehicle
NSS12200LT1G	N/A
NSS1C200LT1G	N/A
NSS60200LT1G	N/A
NSS20200LT1G	N/A
NSS40200LT1G	N/A

Japanese translation of the notification starts here.  
通知の日本語訳はここから始まります。

*Note: The Japanese version is for reference only. In case of any differences between the English and Japanese version, the English version shall control.*

注：日本語版は参照用です。英語版と日本語版の違いがある場合は、英語版が優先されます。





## 信頼性データの要約:

デバイス名: NSV1C200LT1G – PNPRMS: 75941パッケージ: SOT-23

テスト	仕様	条件	間隔	結果
HTRB	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs	0/240
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## 電気的特性の要約:

3つの温度特性と ESD パフォーマンスを実施しています。電気的特性結果は、要請に応じて提供いたします。

## 影響を受ける部品の一覧:

注: 部品一覧には標準部品番号 (既製品) のみが記載されています。本 PCN の影響を受けるカスタム部品番号は、PCN メールで提供される顧客個別の付録、または PCN カスタマイズポータルに記載されています。

部品番号	認定試験用ピークル
NSS12200LT1G	N/A
NSS1C200LT1G	N/A
NSS60200LT1G	N/A
NSS20200LT1G	N/A
NSS40200LT1G	N/A



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**Appendix A: Changed Products**

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**PCN#: FPCN23811X**  
**Issue Date: Jun 21, 2021**

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Product	Customer Part Number	Qualification Vehicle	New Part Number	Replacement Supplier
NSS12200LT1G				
NSS1C200LT1G				
NSS60200LT1G				
NSS20200LT1G				
NSS40200LT1G				